

Amendments to the Specification:

Please replace the paragraph beginning at page 7, lines 30-31 with the following amendment:

FIG. 3 shows the schematic configuration of a fluorometer for distinguish Nd : YAG from Nd : YVO₄. The identical elements to those in FIG. 1 are denoted by the same reference numerals. In this example 2, a semiconductor laser 10 having a wavelength of 809 nm was used as an excitation light source. The transmission peak wavelengths of first, second, and third band-pass filters 11, 12, and 13 were set to 1064 nm, 946 nm, and 1319 nm, respectively. Since the band-pass filters 11, 12, and 13 had a transmittance of about 70%, the amounts of light detected by the second photodetector 5 and the third photodetector 9 were corrected by the amount corresponding to a transmission loss. When the intensity P2 of light transmitted through the second band-pass filter 12 and the intensity P3 of light transmitted through the third band-pass filter 13 are compared with the intensity P1 of light (1064 nm) transmitted through the first band-pass filter 11 as reference, the material can be identified more precisely. That is, differences or relative ratios between P1 and P2 and between P1 and P3 are determined and compared, thereby identifying the material immediately.

Embodiment 3